L Number	Hits	Search Text	DB	Time stamp
1	12135	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46
2	45	((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data) and (identification near3 code))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:47
4	59	(((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (identification near3 code)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:50
3	20	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data) and (identification near3 code)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:58
5	3	("5742173" | "5805472" | "6097204").PN.	USPAT	2003/09/05 14:51
6	12	("4869636" | "5148100" | "5184068" | "5227717" | "5290134" | "5307011" | "5313156" | "5347463" | "5625287" | "5635832" | "5652523" | "5654204").PN.	USPAT	2003/09/05 14:52
7	39	((((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (identification near3 code)))) not (("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data) and (identification near3 code))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 15:01
-	515	"209/573" "209.574"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 16:40
-	7	"6350959"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 18:05
-	4	"6373011"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 18:06
-	55	"5927512"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 18:06
-	0	6373011.URPN.	USPAT	2003/09/03 18:15
-	12135	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46
-	6216	((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 17:06

-	575	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 17:06
-	45	((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data) and (identification near3 code))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46
-	20	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test$3) same ((stor$3 sav$3) and (test result) and (flag data) and (identification near3 code)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 14:46